

<b>Notice of References Cited</b>	Application/Control No. 10/756,777	Applicant(s)/Patent Under Reexamination YEH ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,004,159	01-1977	Rai et al.	365/185.28
*	B	US-5,396,459	03-1995	Arakawa, Hideki	365/185.29
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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